## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Hoppe Docket No.: QIM 2002 P 50212 US

Serial No.: 10/725,938 Art Unit: 2829

Filed: December 3, 2003 Examiner: Nguyen, Vinh P.

For: Testing Apparatus and Method for Testing the Contacting Between a

Semiconductor Device and a Carrier

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## **AMENDMENT**

Dear Sir:

The following amendments and remarks are presented in response to the Examiner's Office Action mailed August 29, 2008. Please amend the above-referenced application as follows.